



Contacts:

Aehr Test Systems

Greg Perkins

V.P. Worldwide Sales & Service

(510) 623-9400 x241

Financial Relations Board

Tricia Ross

Analyst/Investor Contact

(213) 486-6544

**AEHR TEST SYSTEMS RECEIVES ORDER FOR ITS NEW
ADVANCED BURN-IN AND TEST SYSTEM (ABTS)**

Fremont, CA (January 6, 2009) - Aehr Test Systems (Nasdaq: AEHR), a leading supplier of semiconductor test and burn-in equipment, today announced it has received a second order for their new Advanced Burn-in and Test System (ABTS) from a leading European provider of imbedded wireless technology. The system is configured for burning-in and testing advanced logic devices.

“The technology in the ABTS is based on our successful FOXTM-1 full-wafer contact burn-in and test system,” said Greg Perkins, vice president of worldwide sales and service at Aehr Test Systems. “Although numerous FOX systems are currently in high volume production in many parts of the world this will be the first version of the ABTS package part burn-in and test system shipped to Europe. Other members of the ABTS family will focus on high-power logic and memory devices.”

The ABTS family of products is based on a completely new hardware and software architecture that is designed to address not only today’s devices, but also future devices for many years to come. It can test and burn-in memory as well as both high-power logic and low-power logic. It can be configured to provide individual device temperature control for devices up to 50W or more and with up to 320 I/O channels. It uses N+1 redundancy technology for many key components in the system to provide the highest possible system uptime.

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing memory and logic integrated circuits and has an installed base of more than 2,500 systems worldwide. Aehr Test has developed and introduced several innovative products, including the ABTS, FOX, MTX and MAX systems and the DiePak[®] carrier. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC

manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the ABTS technology, acceptance by customers of the ABTS systems shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K, 10-Q and other reports from time to time filed with the Securities and Exchange Commission (SEC) for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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